

RF Power LDMOS Transistors

High Ruggedness N-Channel Enhancement-Mode Lateral MOSFETs

These high ruggedness devices are designed for use in high VSWR industrial, scientific and medical applications, as well as radio and VHF TV broadcast, sub-GHz aerospace and mobile radio applications. Their unmatched input and output design allows for wide frequency range use from 1.8 to 250 MHz.

Typical Performance: $V_{DD} = 50$ Vdc

Frequency (MHz)	Signal Type	P_{out} (W)	G_{ps} (dB)	η_D (%)
40.68	CW	330 CW	26.0	75.0
230 (1)	Pulse (100 μ sec, 20% Duty Cycle)	330 Peak	20.4	75.5

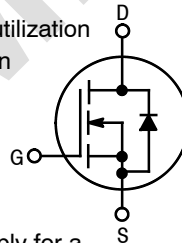
Load Mismatch/Ruggedness

Frequency (MHz)	Signal Type	VSWR	P_{in} (W)	Test Voltage	Result
40.68	Pulse (100 μ sec, 20% Duty Cycle)	> 65:1 at all Phase Angles	2 Peak (3 dB Overdrive)	50	No Device Degradation
230	Pulse (100 μ sec, 20% Duty Cycle)	> 65:1 at all Phase Angles	6 Peak (3 dB Overdrive)	50	No Device Degradation

1. Measured in 230 MHz typical narrowband fixture.

Features

- Unmatched input and output allowing wide frequency range utilization
- Two opposite pin-connection versions (A and B) to be used in a push-pull, two-up configuration
- Characterized from 30 to 50 V
- Suitable for linear application
- Integrated ESD protection with greater negative gate-source voltage range for improved Class C operation
- Included in NXP product longevity program with assured supply for a minimum of 15 years after launch



Typical Applications

- Industrial, scientific, medical (ISM)
 - Laser generation
 - Plasma etching
 - Particle accelerators
 - MRI and other medical applications
 - Industrial heating, welding and drying systems
- Broadcast
 - Radio broadcast
 - VHF TV broadcast
- Aerospace
 - VHF omnidirectional range (VOR)
 - HF and VHF communications
 - Radar
- Mobile radio
 - VHF and UHF base stations
 - Amateur radio
 - Switch mode power supplies

This document contains information on a preproduction product. Specifications and information herein are subject to change without notice.

MRF300AN
MRF300BN
PREPRODUCTION

1.8–250 MHz, 300 W CW, 50 V
WIDEBAND
RF POWER LDMOS TRANSISTORS

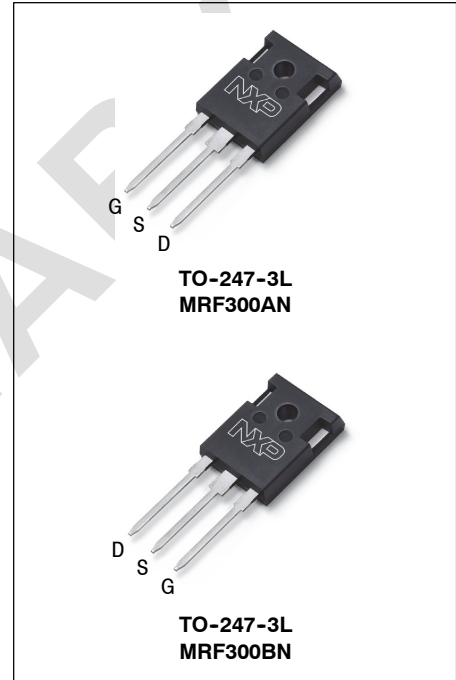


Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	-0.5, +133	Vdc
Gate-Source Voltage	V_{GS}	-6.0, +10	Vdc
Operating Voltage	V_{DD}	50	Vdc
Storage Temperature Range	T_{stg}	-65 to +150	°C
Case Operating Temperature Range	T_C	-40 to +150	°C
Operating Junction Temperature Range (1,2)	T_J	-40 to +175	°C
Total Device Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25°C	P_D	97 0.72	W W/°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value (2,3)	Unit
Thermal Resistance, Junction to Case CW: Case Temperature 76°C, 300 W CW, 50 Vdc, $I_{DQ} = 50$ mA, 40.68 MHz	$R_{\theta JC}$	0.55	°C/W
Thermal Impedance, Junction to Case Pulse: Case Temperature 74°C, 300 W Peak, 100 μsec Pulse Width, 20% Duty Cycle, 50 Vdc, $I_{DQ} = 100$ mA, 230 MHz	$Z_{\theta JC}$	0.13	°C/W

Table 3. ESD Protection Characteristics

Test Methodology	Class
Human Body Model (per JS-001-2017)	2, passes 2500 V
Charge Device Model (per JS-002-2014)	C3, passes 1200 V

Table 4. Moisture Sensitivity Level

Test Methodology	Rating	Package Peak Temperature	Unit
Per JESD22-A113, IPC/JEDEC J-STD-020	0	260	°C

Table 5. Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Off Characteristics					
Gate-Source Leakage Current ($V_{GS} = 5$ Vdc, $V_{DS} = 0$ Vdc)	I_{GSS}	—	—	1	μAdc
Drain-Source Breakdown Voltage ($V_{GS} = 0$ Vdc, $I_D = 30$ μAdc)	$V_{(BR)DSS}$	133	—	—	Vdc
Zero Gate Voltage Drain Leakage Current ($V_{DS} = 100$ Vdc, $V_{GS} = 0$ Vdc)	I_{DSS}	—	—	10	μAdc
On Characteristics					
Gate Threshold Voltage ($V_{DS} = 10$ Vdc, $I_D = 2130$ μAdc)	$V_{GS(th)}$	1.7	2.2	2.7	Vdc
Gate Quiescent Voltage ($V_{DD} = 50$ Vdc, $I_D = 100$ mAdc, Measured in Functional Test)	$V_{GS(Q)}$	2.0	2.5	3.0	Vdc
Drain-Source On-Voltage ($V_{GS} = 10$ Vdc, $I_D = 2.4$ Adc)	$V_{DS(on)}$	—	0.16	—	Vdc
Forward Transconductance ($V_{DS} = 10$ Vdc, $I_D = 36$ Adc)	g_{fs}	—	33.5	—	S

1. Continuous use at maximum temperature will affect MTTF.

2. MTTF calculator available at <http://www.nxp.com/RF/calculators>. (Calculator available when part is in production.)

3. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.nxp.com/RF> and search for AN1955.

(continued)

Table 5. Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted) (continued)

Characteristic	Symbol	Min	Typ	Max	Unit
Dynamic Characteristics (1)					
Reverse Transfer Capacitance ($V_{DS} = 50\text{ Vdc} \pm 30\text{ mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0\text{ Vdc}$)	C_{rss}	—	2.31	—	pF
Output Capacitance ($V_{DS} = 50\text{ Vdc} \pm 30\text{ mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0\text{ Vdc}$)	C_{oss}	—	104	—	pF
Input Capacitance ($V_{DS} = 50\text{ Vdc}$, $V_{GS} = 0\text{ Vdc} \pm 30\text{ mV(rms)ac}$ @ 1 MHz)	C_{iss}	—	403	—	pF

Typical Narrowband Performance – 230 MHz (In NXP Narrowband 230 MHz Fixture, 50 ohm system) $V_{DD} = 50\text{ Vdc}$, $I_{DQ} = 100\text{ mA}$, $P_{in} = 3\text{ W}$, $f = 230\text{ MHz}$, 100 μsec Pulse Width, 20% Duty Cycle

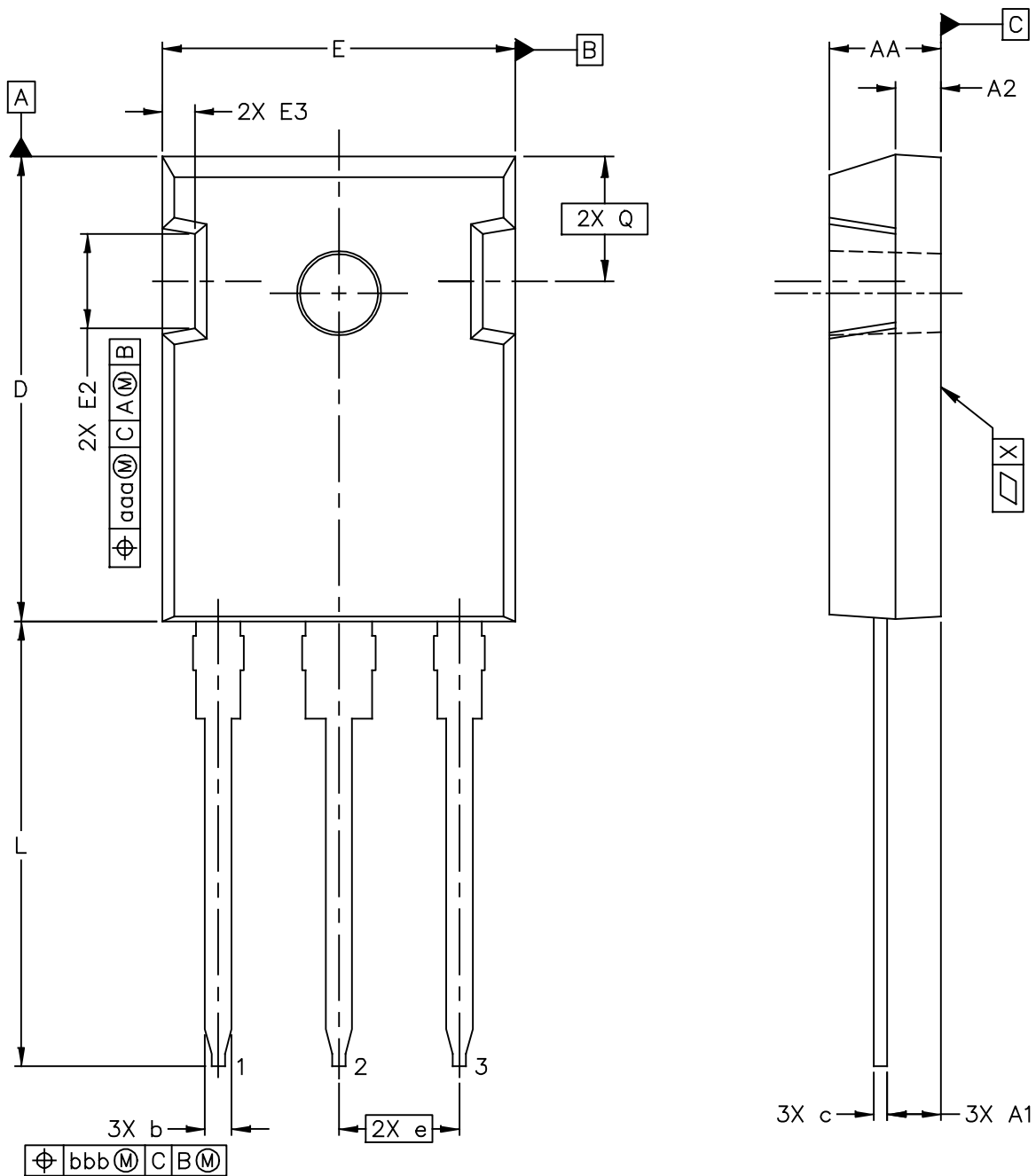
Common-Source Amplifier Output Power	P_{out}	—	330	—	W
Drain Efficiency	η_D	—	75.5	—	%
Input Return Loss	IRL	—	-21	—	dB

Table 6. Load Mismatch/Ruggedness (In NXP Production Fixture, 50 ohm system) $I_{DQ} = 100\text{ mA}$

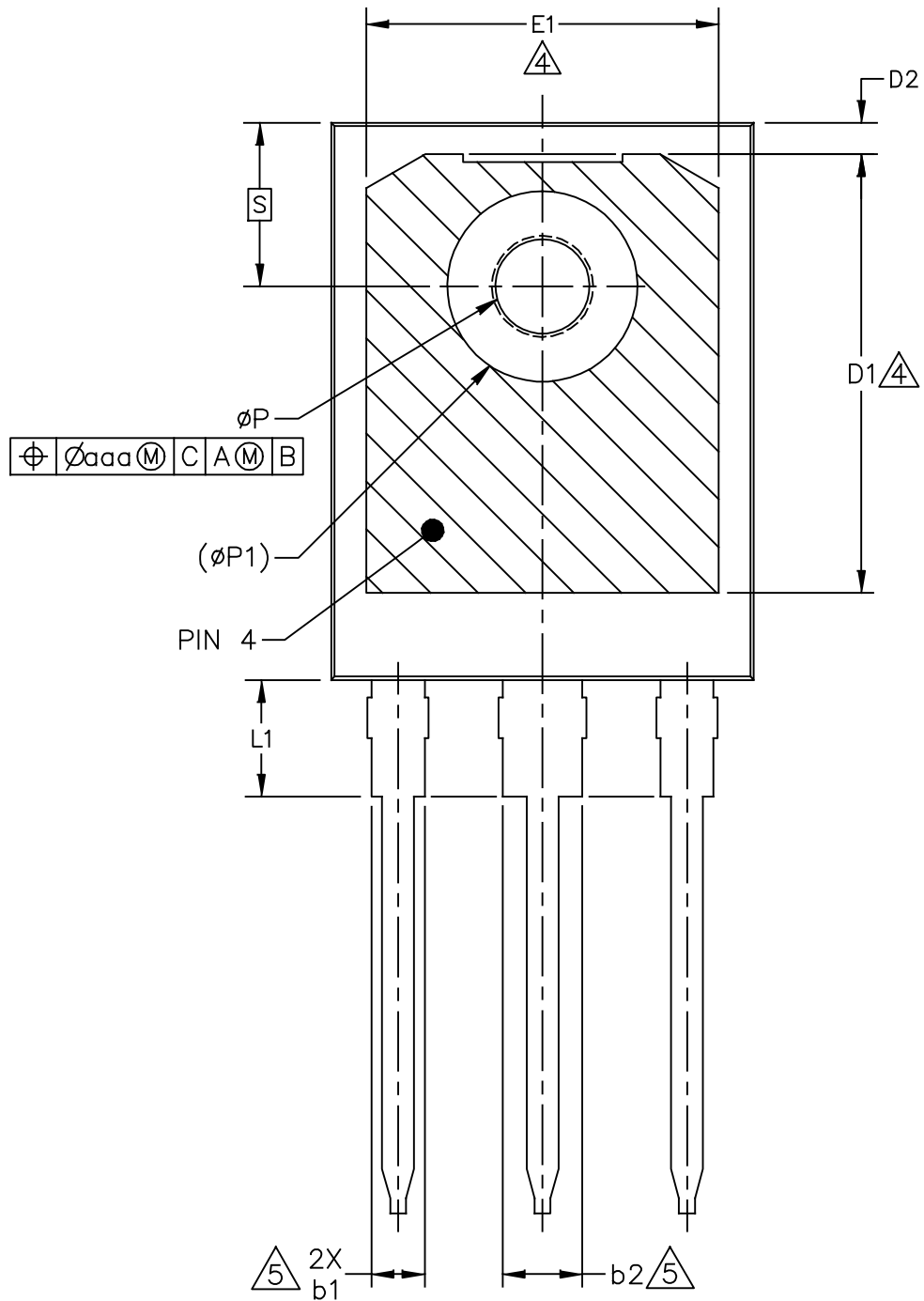
Frequency (MHz)	Signal Type	VSWR	P_{in} (W)	Test Voltage, V_{DD}	Result
230	Pulse (100 μsec , 20% Duty Cycle)	> 65:1 at all Phase Angles	6 Peak (3 dB Overdrive)	50	No Device Degradation

1. Each side of device measured separately.

PACKAGE DIMENSIONS





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NOIES:

1. CONTROLLING DIMENSION: MILLIMETER, ANGLES ARE IN DEGREES.
2. INTERPRET DIMENSIONS AND TOLERANCES AS PER ASME Y14.5M-1994.
3. DIMENSION D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.13 MM (.005 INCH) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREME OF THE PLASTIC BODY.
4.  HATCHING REPRESENTS THE EXPOSED AREA OF THE THERMAL PAD (PIN 4). DIMENSIONS D1 AND E1 REPRESENT THE VALUES BETWEEN THE TWO OPPOSITE POINTS ALONG THE EDGES OF THE EXPOSED AREA OF THE THERMAL PAD. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION D1 AND E1.
5.  DIMENSIONS b1 & b2 DO NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.15 MM (.006 INCH) PER SIDE IN EXCESS OF THE DIMENSIONS b1 & b2 AT MAXIMUM MATERIAL CONDITION.
6. EJECTOR MARKS ON TOP SURFACE ARE PERMITTED AND IT IS SUPPLIER OPTION. THE MAXIMUM DEPTH OF EJECTOR MARK IS 0.25 MM (.010 INCH)
7. ϕ P TO HAVE MAXIMUM DRAFT ANGLE 1.5°.

DIM	INCH		MILLIMETER		DIM	INCH		MILLIMETER	
	MIN	MAX	MIN	MAX		MIN	MAX	MIN	MAX
AA	.190	.205	4.83	5.21	E3	.039	.102	0.99	2.60
A1	.090	.100	2.29	2.54	e	.214 BSC		5.44 BSC	
A2	.075	.085	1.90	2.16	L	.780	.800	19.80	20.32
b	.042	.052	1.07	1.33	L1	---	.173	---	4.40
b1	.075	.095	1.91	2.41	P	.138	.146	3.50	3.71
b2	.113	.133	2.87	3.38	P1	---	.291	---	7.40
c	.022	.027	0.55	0.69	Q	.228 BSC		5.79 BSC	
D	.819	.831	20.80	21.11	S	.242 BSC		6.15 BSC	
D1	.515	---	13.08	---	X	---	.004	---	0.01
D2	.020	---	0.51	---	aaa	.025		0.64	
E	.618	.635	15.70	16.13	bbb	.010		0.25	
E1	.487	---	12.37	---					
E2	.145	.201	3.68	5.11					
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